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## Technical Compliance

No. ACS-E18020-1

The following product has been tested by us with the listed standards and found in compliance with the council EMC directive 2014/30/EU. It is demonstrative for the compliance with this EMC Directive.

Submitter : TPV Electronics (FuJian) Co., Ltd.

Rongqiao Economic and Technological Development Zone, Fuqing

City, Fujian Province, P.R. China

Product : LCD Monitor

Model No. : QM-75\*\*\*\*(\*=A-Z, a-z, 0-9, hyphen, \ or blank)

Brand : AG neovo

	Test Standards:	
EN 55032: 2012+AC:2013 (Class A) CISPR 32: 2012 (AS/NZS CISPR 32: 2015)	Electromagnetic compatibility of multimedia equipment - Emission requirements	
EN 61000-3-2: 2014	Electromagnetic compatibility(EMC) Part 3-2:Limits-Limits for harmonic current emissions(equipment input current ≤ 16A per phase)	
EN 61000-3-3: 2013	Electromagnetic compatibility(EMC) Part 3-3:Limits-Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16A per phase and not subject to conditional connection	
EN 55024: 2010 EN 55024: 2010+A1:2015	Information technology equipment-Immunity characteristics limits and methods of measurement	
	IEC 61000-4-2: 2008	Electrostatic Discharge
	IEC 61000-4-3: 2010	RF Field Strength Susceptibility
	IEC 61000-4-4: 2012	Electrical Fast Transients
	IEC 61000-4-5: 2014	Surge
	IEC 61000-4-6: 2013	Conducted Susceptibility
	IEC 61000-4-8: 2009	Magnetic Field Immunity
	IEC 61000-4-11: 2004	Dips / Voltage Interruption Variation

IDX \*\*\* \*\*\*

Audix Technology (Shenzhen) Co., Ltd.

EMC部門報告專用章

Stamp only for EMC Dept. Report

Signature:

David Jin Manager

Date: May.09,2018

The technical compliance is based on a single evaluation of one sample of above mentioned product. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.